

Docket No.: 87326.3920

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Jeffrey M. BROWN, et al.

Serial No. 10/646,846

Filed: August 25, 2003

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: Group Art Unit: 2681

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: Examiner: Not yet assigned

For: APPARATUS AND METHOD FOR MONITORING TRANSMISSION SYSTEMS
USING EMBEDDED TEST SIGNALS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

These references were cited in the International Search Report dated 23 February 2005. No further elaboration is believed necessary. Copies of the search report and cited art are submitted herewith in accordance with 37 C.F.R. 1.98(a).

AUTHORIZATION

No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

Respectfully submitted,

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LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.

87326.3920

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APPLICANT

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FILING DATE

August 25, 2003

GROUP

2681

U.S. PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A		5,416,623	5/16/95	Dawson et al.	359	110	12/17/91
B		3,651,403	3/21/72	Fluck, Jr.	325	31	5/18/70
C		2003/0142017	7/31/03	Rabinowitz et al.	342	458	1/28/03
D		5,585,842	12/17/96	Chappell et al.	348	192	9/19/94
E							
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G							
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J							
K							
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FOREIGN PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U		WO 99/38023	7/29/99	WIPO	G01R	31/11	
V		WO 01/15001	3/1/01	WIPO	G06F	17/00	
W		0 902 385	3/17/99	Europe	G06K	1/12	
X		WO 03/088683	10/23/03	WIPO	H04N	17/00	
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

HH		
II		
JJ		
KK		
LL		
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NN		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.